
Delay and power calculation standards - Part 1: Integrated circuit delay and power calculation systems (IEC 61523-1:2001)

Delay and power calculation standards -- Part 1: Integrated circuit delay and power calculation systems

Berechnung von Verzögerung und Leistungsaufnahme beim Entwurf von Chips -- Teil 1: System zur Berechnung von Verzögerung und Leistungsaufnahme integrierter Schaltkreise (IC)

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Normes de calculs de puissance
et de temps de retard
Partie 1: Systèmes de calcul
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(CEI 61523-1:2001)

Berechnung von Verzögerung
und Leistungsaufnahme beim
Entwurf von Chips
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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 93/143/FDIS, future edition 1 of IEC 61523-1, prepared by IEC TC 93, Design automation, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61523-1 on 2001-12-04.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2002-09-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2004-12-01

This standard is based on IEEE Std P1481:1999; IEEE Standard for delay and power calculation systems.

Endorsement notice

The text of the International Standard IEC 61523-1:2001 was approved by CENELEC as a European Standard without any modification.

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Part 1: Integrated circuit delay and power calculation systems

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

DELAY AND POWER CALCULATION STANDARDS –**Part 1: Integrated circuit delay and power calculation systems**

FOREWORD

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International Standard IEC 61523-1 has been prepared by IEC technical committee 93: Design automation.

This standard is based on IEEE Std P1481 (1999): *IEEE Standard for delay and power calculation systems*.

The text of this standard is based on the following documents:

FDIS	Report on voting
93/143/FDIS	93/144/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This standard does not follow the rules for the structure of international standards given in Part 3 of the ISO/IEC Directives.

IEC 61523 consists of the following parts, under the general title: *Delay and calculation standards*:

IEC 61523-1, Part 1: *Integrated circuit delay and power calculation systems*

IEC 61523-2, Part 2: *Prelayout delay calculation model specification of CMOS ASIC libraries* (to be published)

The committee has decided that the contents of this publication will remain unchanged until 2006. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

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